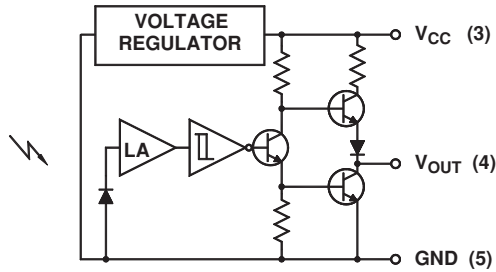
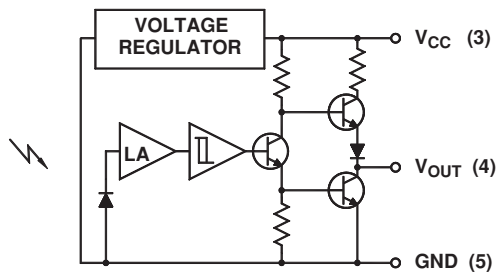


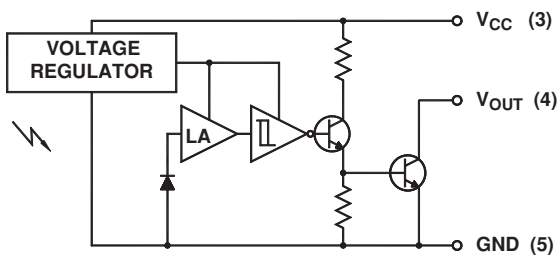
QSE156 QSE157 QSE158 QSE159



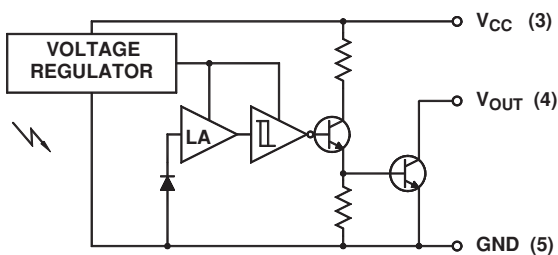
QSE156
Totem-Pole Output Buffer



QSE157
Totem-Pole Output inverter



QSE158
Open-Collector Output Buffer



QSE159
Open-Collector Output Inverter

QSE156 QSE157 QSE158 QSE159

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit
Operating Temperature	T_{OPR}	-40 to +85	$^\circ\text{C}$
Storage Temperature	T_{STG}	-40 to +100	$^\circ\text{C}$
Soldering Temperature (Iron) ^(2,3,4)	T_{SOL-I}	240 for 5 sec	$^\circ\text{C}$
Soldering Temperature (Flow) ^(2,3)	T_{SOL-F}	260 for 10 sec	$^\circ\text{C}$
Output Current	I_O	50	mA
Supply Voltage	V_{CC}	4.0 to 16	V
Output Voltage	V_O	30	V
Power Dissipation ⁽¹⁾	P_D	100	mW

NOTES:

1. Derate power dissipation linearly 2.50 mW/ $^\circ\text{C}$ above 25 $^\circ\text{C}$.
2. RMA flux is recommended.
3. Methanol or isopropyl alcohols are recommended as cleaning agents.
4. Soldering iron 1/16" (1.6 mm) minimum from housing.
5. $\lambda = 880 \text{ nm}$ (AlGaAs).

ELECTRICAL / OPTICAL CHARACTERISTICS ($T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$, $V_{CC} = 4.5$ to 16 volts)

Parameter	Symbol	Min	Typ	Max	Units	Test Conditions
Positive Going Threshold Irradiance ⁽⁵⁾	Ee (+)	0.025		0.250	mW/cm ²	$T_A = 25^\circ\text{C}$
Hysteresis Ratio	Ee (+)/Ee(-)	1.10		2.00		
Supply Current	I_{CC}	—		5.0	mA	Ee = 0 or .3 mW/cm ² (⁵)
Peak to peak ripple which will cause false triggering		—		2.00	V	f = DC to 50 MHz
QSE156 (BUFFER TOTEM POLE)						
High Level Output Voltage	V_{OH}	$V_{CC}-2.1$		—	V	Ee = .3 mW/cm ² , $I_{OH} = -1.0\text{mA}$ (⁵)
Low Level Output Voltage	V_{OL}	—		0.40	V	Ee = 0, $I_{OL} = 16 \text{ mA}$
QSE157 (INVERTER TOTEM POLE)						
High Level Output Voltage	V_{OH}	$V_{CC}-2.1$		—	V	Ee = 0, $I_{OH} = -1.0\text{mA}$
Low Level Output Voltage	V_{OL}	—		0.40	V	Ee = .3 mW/cm ² , $I_{OL} = 16\text{mA}$ (⁵)
QSE158 (BUFFER OPEN COLLECTOR)						
High Level Output Current	I_{OH}	—		100	μA	Ee = .3mW/cm ² , $V_{OH} = 30\text{V}$ (⁵)
Low Level Output Voltage	V_{OL}	—		0.40	V	Ee = 0, $I_{OL} = 16\text{mA}$
QSE159 (INVERTER OPEN COLLECTOR)						
High Level Output Current	I_{OH}	—		100	μA	Ee = 0, $V_{OH} = 30\text{V}$
Low Level Output Voltage	V_{OL}	—		0.40	V	Ee = .3mW/cm ² , $I_{OL} = 16\text{mA}$ (⁵)
QSE156, QSE157						
Output rise, fall times	tr, tf	—		70	nS	Ee = 0 or .3 mW/cm ² , f = 10KHz
Propagation delay	tphl, tplh		6.0		μS	DC = 50%, $R_L = 360\Omega$ (⁵)
QSE158, QSE159						
Output rise, fall times	tr, tf	—		100	nS	Ee = 0 or .3 mW/cm ² , f = 10KHz
Propagation delay	tphl, tplh		6.0		μS	DC = 50%, $R_L = 360\Omega$ (⁵)

QSE156 QSE157 QSE158 QSE159

Typical Performance Curves - (Sensor Coupled to QEE113 Emitter)

Fig. 1 Output Voltage vs. Input Current (Inverters)

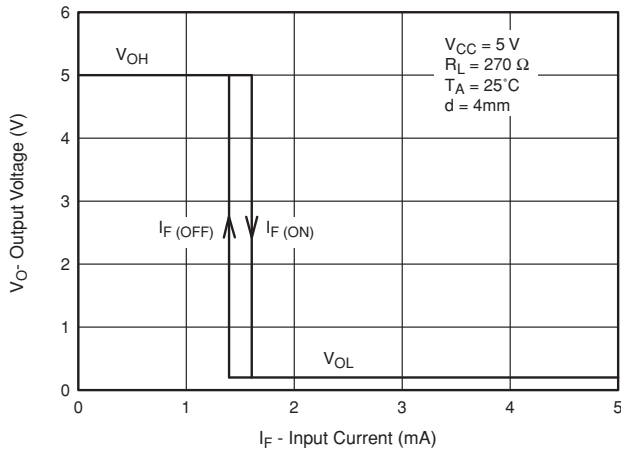


Fig. 2 Output Voltage vs. Input Current (Buffers)

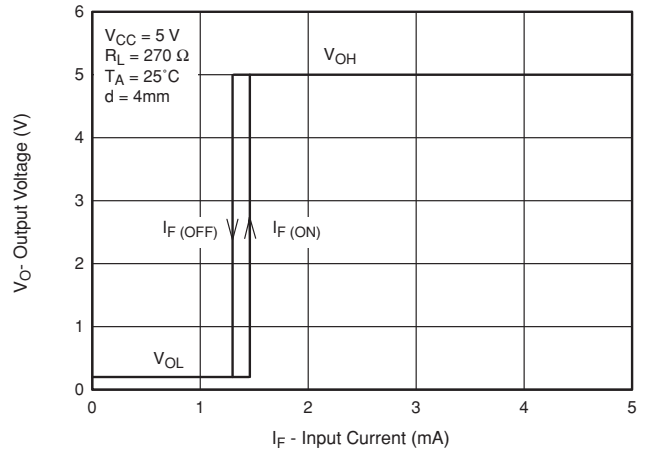


Fig. 3 Threshold Current vs. Distance

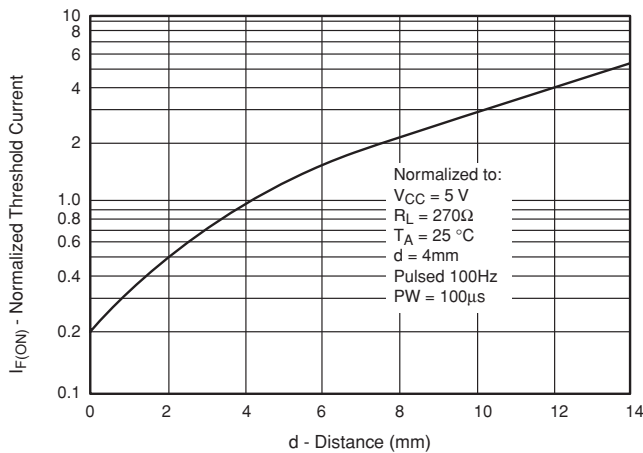
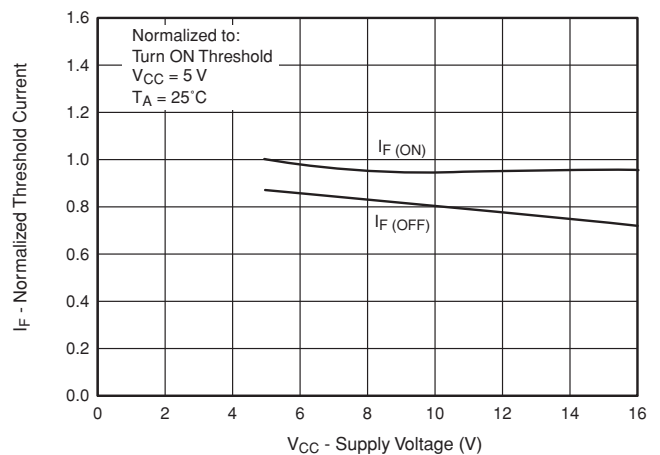


Fig. 4 Normalized Threshold Current vs. Supply Voltage



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Fig. 5 Normalized Threshold Current vs. Ambient Temperature

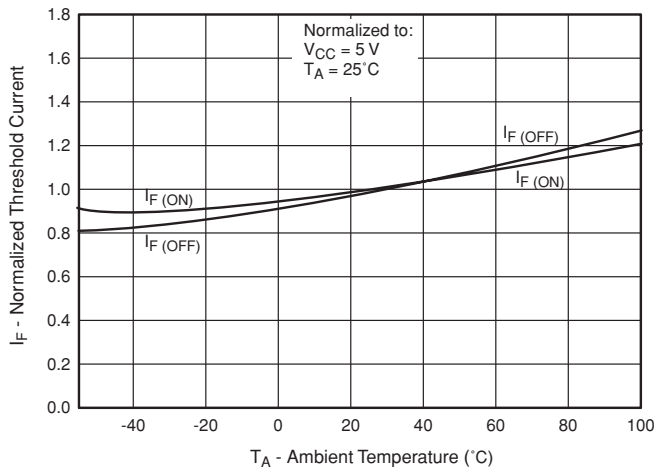


Fig. 6 Low Output Voltage vs. Output Current

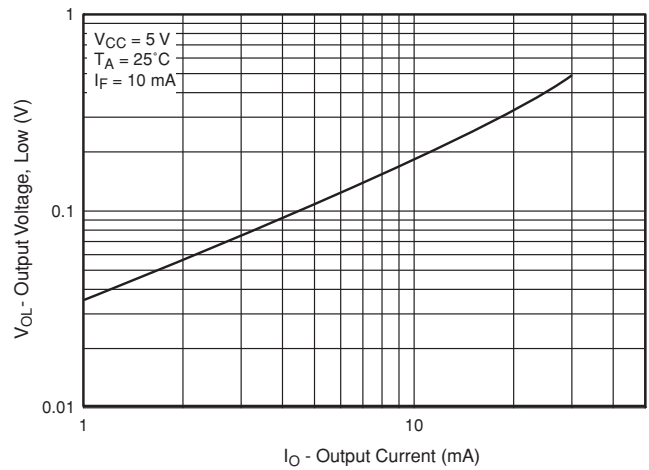
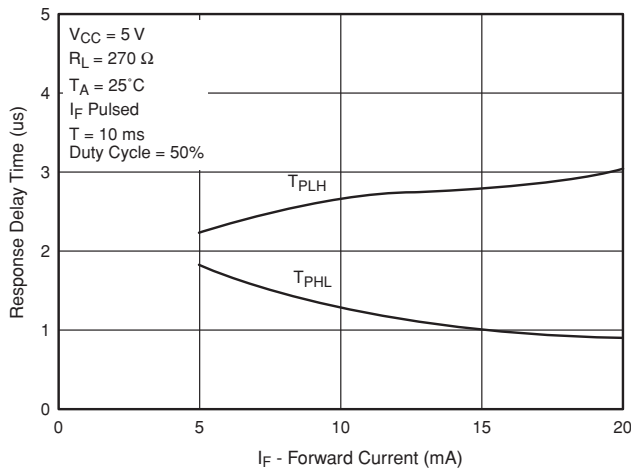
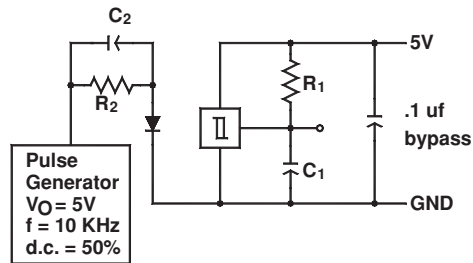


Fig. 7 Response Time vs. Forward Current



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Fig. 8 Switching Speed Test Circuit



$R_1 = 360 \Omega$
 $R_2 = 180 \Omega$

$C_1 = 15 \text{ pf}$
 $C_2 = 20 \text{ pf}$

C_1 and C_2 include probe and
stray wire capacitance

Fig. 9 Switching Times Definition for Buffers

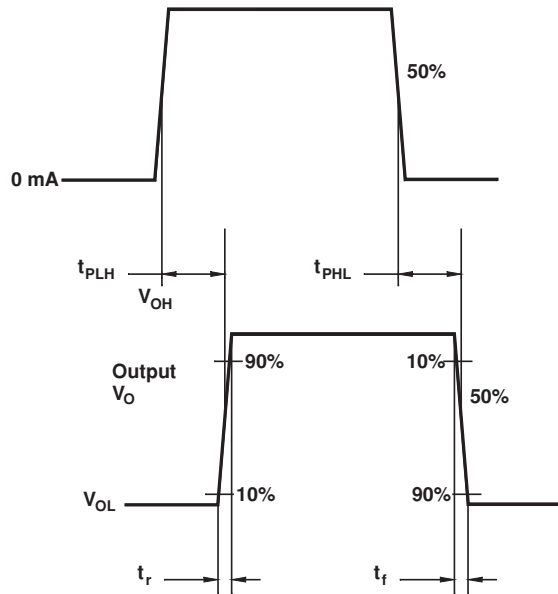
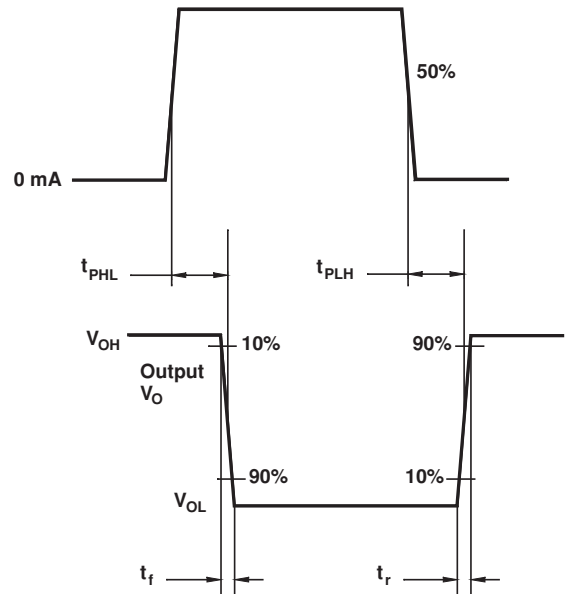


Fig. 10 Switching Times Definition for Inverters



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